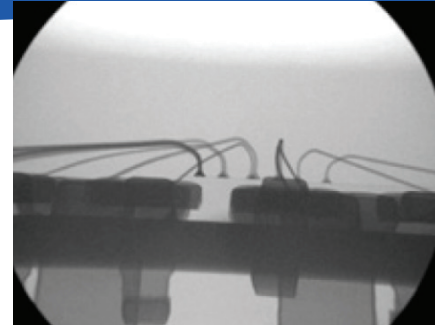
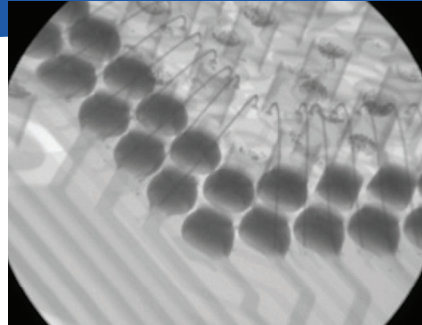
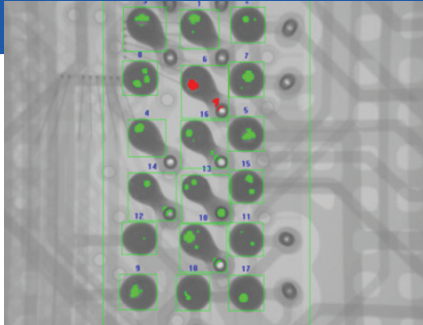


Post-Processing Software

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Vital to quality control, NAI Industrial software allows manufacturers to find contamination, scratches, cracks, blemishes, gaps, pits and other production flaws. Post-processing software can detect defects invisible to the human eye – faster and more accurately.

We offer several user-friendly software packages to meet a variety of applications for a wide range of industries. Choose from one of our three software packages or let us put together a customized package to fit your unique needs. Contact Josh Hunt at 805.383.2214 or jhunt@NAImaging.com for more information.

Standard Software Package

- Image capturing and saving (.jpg, .bmp, .tif)
- Auto Live image averaging
- Post capture image enhancements:
 - *Brightness and contrast adjustments*
 - *Image filters (sharpen, psuedo color, negative)*
- Point-to-point distance measurement tool
- Measurement calibration (inches, mm, mils)
- Image annotation tool:
 - *On screen text tool*
 - *Arrow drawing*
 - *Line, circular or rectangular shape drawing*
- Quad view imaging tool (allows user to capture four images and combine them into one picture)

Optimum Software Package

- Standard Software Package features
- BGA measurement algorithm tools
- Solder ball size:
 - *Ball area*
 - *Ball diameter*
 - *Ball roundness*
 - *Percent void*
 - *Pass fail criteria*
 - *Image reporting*

Advanced Software Package

- Optimum Software Package features
- QFN measurement algorithm tools:
 - *Joint area*
 - *Percent void*
 - *Pass/fail criteria*
- Semiconductor measurement algorithm tools:
 - *Bond wire sweep*
 - *Die attach void measurement*
 - *Pass/fail criteria*
- Gull wing joint measurement algorithm tools:
 - *Joint area*
 - *Percent void*
 - *Pass/fail criteria*
 - *Drill offset measurement*
 - *Center to center offset (X & Y distance)*